

Notice of References Cited	Application/Control No. 09/783,657	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Anh Ly	Art Unit 2162	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,519,597	02-2003	Cheng et al.	707/10
	B	US-6,480,865	11-2002	Lee et al.	715/523
	C	US-6,418,448	07-2002	Sarkar, Shyam Sundar	707/104.1
	D	US-6,785,673	08-2004	Fernandez et al.	707/3
	E	US-6,549,922	04-2003	Srivastava et al.	707/205
	F	US-2002/0133484	09-2002	Chau et al.	707/3
	G	US-5,548,749	08-1996	Kroenke et al.	707/102
	H	US-6,701,321	03-2004	Tsai, Daniel E.	707/102
	I	US-5,995,969	11-1999	Lee et al.	707/100
	J	US-5,764,978	06-1998	Masumoto, Toshihiko	707/100
	K	US-5,499,371	03-1996	Henninger et al.	717/108
	L	US-6,163,776	12-2000	Periwal, Damodar D.	707/4
	M	US-6,523,036	02-2003	Hickman et al.	707/10

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.